

Notice of References Cited	Application/Control No. 10/066,105	Applicant(s)/Patent Under Reexamination BEIER ET AL.	
	Examiner Hai C Pham	Art Unit 2861	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,563,601 B1 ✓	05-2003	Yamada et al.	358/1.9
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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